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Burn-in & Test Strategies Workshop

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Burn-in & Test Strategies Workshop

Poster Session



Burn-in & Test Strategies Workshop www.bitsworkshop.org

March 15-18, 2015



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Contact Resistance Change with Cleaning Numbers

Significant Leakage Cause from Brush Cleaning

경인플라켐 AIS2100 SEI WD = 21.3 20.00 kV X 2.5K 10um

The debris and particles on the crown valley and the surfaces generated after brush cleaning could be a significant leakage cause during the test.

Conclusions

- From the SEM/EDS analysis, the Au coating and the tip was worn out after 60 shots of the brush cleaning. There was no significant surface change even after 300 shots of laser cleaning.
- From Rc measurement, the contact resistance increased more than 100% after 300 shots of brush cleaning. There was no significant change after laser cleaning.
- It was found that the surface became very rough and lots of debris accumulated inside the crown surface. The debris and particle from the surface could be a significant cause of leakage during the test.

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Laser Cleaning vs Brush Cleaning

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